INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)					Docket Number (Optional) POU920030178US1		Application Number NYA			
					Applicant(s) Motika, et al.			IVIA		
					Filing Date Group Art Unit					
					NYA		NYA			
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EXAMINER		/Phung Chung/			DATE CONSIDERED 12/06/2006					
EXAMINE not conside	R: Initi red. In	al if citation considered, whether clude copy of this form with next	or not citation is in communication to	conforman	ce with MPEP Section 609; I)raw line thro	igh citation if no	t in conform	ance and	
not considered. Include copy of this form with next communication to applicant.										

Application Number Docket Number (Optional) POU920030178US1 NYA INFORMATION DISCLOSURE CITATION Applicant(s) Motika, et al. (Use several sheets if necessary) Filing Date Group Art Unit NYA NYA *EXAMINER OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) INITIAL Bernd Konemann, Joachim Mucha and Gunther Zwiehoff, "Built-In Test for Complex Digital Integrated Circuits", June 1980, IEEE Journal of Solid State Circuits, Vol. SC-15, No. 3, pp. 315-319. PC **EXAMINER** DATE CONSIDERED 12/06/2006 /Phung Chung/ EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and

not considered. Include copy of this form with next communication to applicant.